

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:

B. S. Beaman et al.

Serial No.: 10/145,661

Filed: May 14, 2002

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE  
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Date: June 4, 2007

Group Art Unit: 2829

Examiner: J. M. Hollington

Docket No.: YOR919990088US1

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**SUPPLEMENTAL RESPONSE TO OFFICE ACTION DATED MARCH 1, 2007**

Sir:

In response to the Office Action dated March 1, 2007, please amend the  
above-identified application as follows:

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 5 of this paper.